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## Application Number INFORMATION **DISCLOSURE STATEMENT** Filing Date TRANSMITTAL First Named Inventor PINEDA DE GYVEZ, Jose 2816 Group Art Unit To Commissioner For Patents Enclosed herewith is a Form PTO-1449, any required copies of Examiner Name documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97. NL02 1186 US Atty. Docket Number **U.S. PATENT DOCUMENTS** Examine Cite Document Number No.-Kind Code<sup>2</sup> (if known) Publication Date MM-DD-YYYY Name of Patentee or Pages, Columns Lines, Where Relevant No. **Applicant of Cited Document** Passages or Relevant Figures Appear us- 6,040,728 3/21/2000 US-USus-<del>US.</del> **FOREIGN PATENT DOCUMENTS** Pages, Columns Lines. Examiner **Document Number Publication Date** Name of Patentee or Where Relevant Passages Initials\* Nο (ctry3-no.4-kind5, if known) MM-DD-YYYY Applicant of cited document or Relevant Figures Appear NON-PATENT LITERATURE DOCUMENTS Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. Examiner Cite Initials\* No. LIU T ET AL: "A negative feedback based substrate coupling noise reduction method", ASIC/SOC Conference, 1999. PROCEEDINGS. TWELFTH ANNUAL IEEE INTERNATIONAL, WASHINGTON, DC, USA 15-18 SEPT. 1999, PISCATAWAY, NJ, USA, IEEE, US, 9/15/1999, pages 49-53 CHAN H.H Y ET AL: "Substrate coupled noise reduction and active noise suppression circuits for mixed-signal system-on-a-chip designs" PROCEEDINGS OF THE 44TH, IEEE 2001 MIDWEST SYMPOSIUM ON CIRCUITS AND SYSTEMS. MWSCAS 2001. DAYTON, OH, AUG. 14-17, 2001. MIDWEST SYMPOSIUM ON CIRCUITS AND SYSTEMS, NEW YORK, NY: IEEE, US, vol. 1 of 2. 8/14/2001, pages 154-157 Examiner Date

Considered

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<sup>\*</sup> EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 18 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.